



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/622,015

Applicants: Daniel C. Cowles, et al.

Filed: July 17, 2003

Title: METHODS OF SAMPLING HALOSILANES FOR METAL ANALYTES

TC/A.U. Unknown

Examiner: Unknown

Attorney Docket: Serie 6184

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98. Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited on the enclosed PTO Form 1449 is enclosed.

No fee is due at this time in accordance with 37 C.F.R. § 1.97. However, the Commissioner is hereby authorized to charge any appropriate fees under 37 C.F.R. §§ 1.16, 1.17 and 1.21 that may be required by this paper, and to credit any overpayment, to Deposit Account No. 01-1375.

This paper is submitted in duplicate. To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

Linda K. Russell

Registration No. 34,918

Date: 12/17/2003

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Form PTO-1449 (modified)

Atty. Docket No.  
2096.001300/Serie: 6184Serial No.  
10/622,015

## List of Patents and Publications for Applicant's

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant

Cowles and Bollinger

Filing Date:

July 17, 2003

Group:

1743

## U.S. Patent Documents

See Page

## Foreign Patent Documents

See Page

## Other Art

See Page 1

## U.S. Patent Documents

| Exam. Init. | Ref. Des. | Document Number | Date | Name | Class | Sub Class | Filing Date of App. |
|-------------|-----------|-----------------|------|------|-------|-----------|---------------------|
|             |           |                 |      |      |       |           |                     |

## Foreign Patent Documents

| Exam. Init. | Ref. Des. | Document Number | Date | Country | Class | Sub Class | Translation Yes/No |
|-------------|-----------|-----------------|------|---------|-------|-----------|--------------------|
|             |           |                 |      |         |       |           |                    |

## Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

| Exam. Init. | Ref. Des. | Citation  |
|-------------|-----------|---|
|             | C1        | Chen <i>et al.</i> , "Spectrophotometric Determination of Trace and Ultratrace Levels of Boron in Silicon and Chlorosilane Samples," <i>Fresenius J. Anal. Chem.</i> , 340:357-362, 1991.   |
|             | C2        | Cowles and Bollinger, "Point-of-Use Sampling and Metal Analysis for Trichlorosilane," <i>SEMI Technical Symposium (STS): Innovations in Semiconductor Manufacturing</i> , July 2002.  |
|             | C3        | Stolyarova and Orlova, "Trichlorosilane and Silicon Tetrachloride Sample Preparation for Trace Boron, Phosphorus, and Arsenic Determination," <i>J. Anal. Chem.</i> , 50(2):130-134, 1995.  |
|             | C4        | Wei and Yang, "Determination of Phosphorus and Arsenic in Trichlorosilane by Electrothermal Vaporization-Inductively Coupled Plasma Mass Spectrometry with Prior Concentration by Cuprous Chloride," <i>Fresenius J. Anal. Chem.</i> , 353:167-170, 1995. |
|             | C5        | Presentation of POU Sampling and Metal Analysis of Trichlorosilane at SEMI Semiconductor Equipment and Materials International, July 2002.  |

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.